

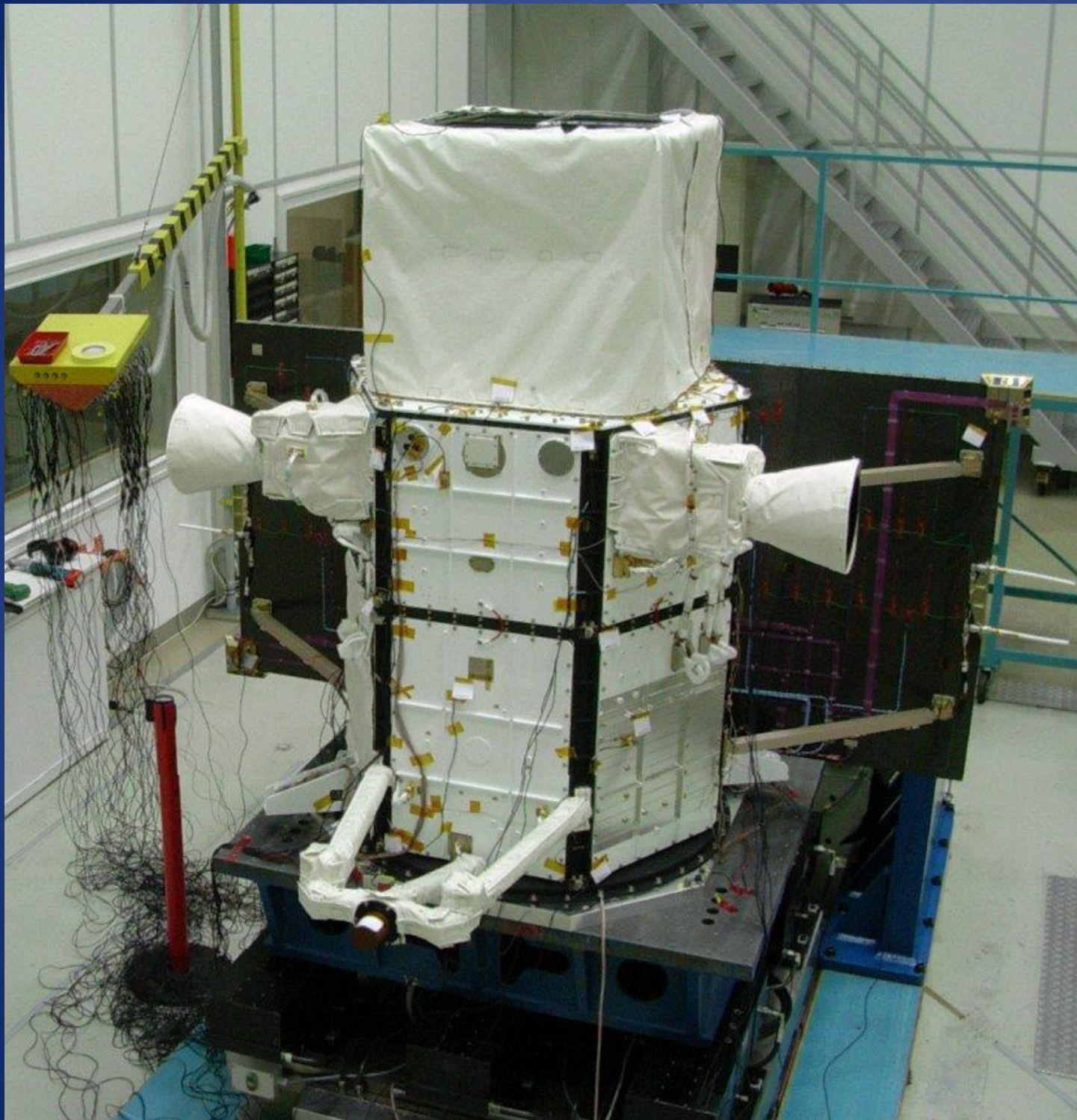
Possible effects on avionics induced by Terrestrial Gamma-Ray Flashes

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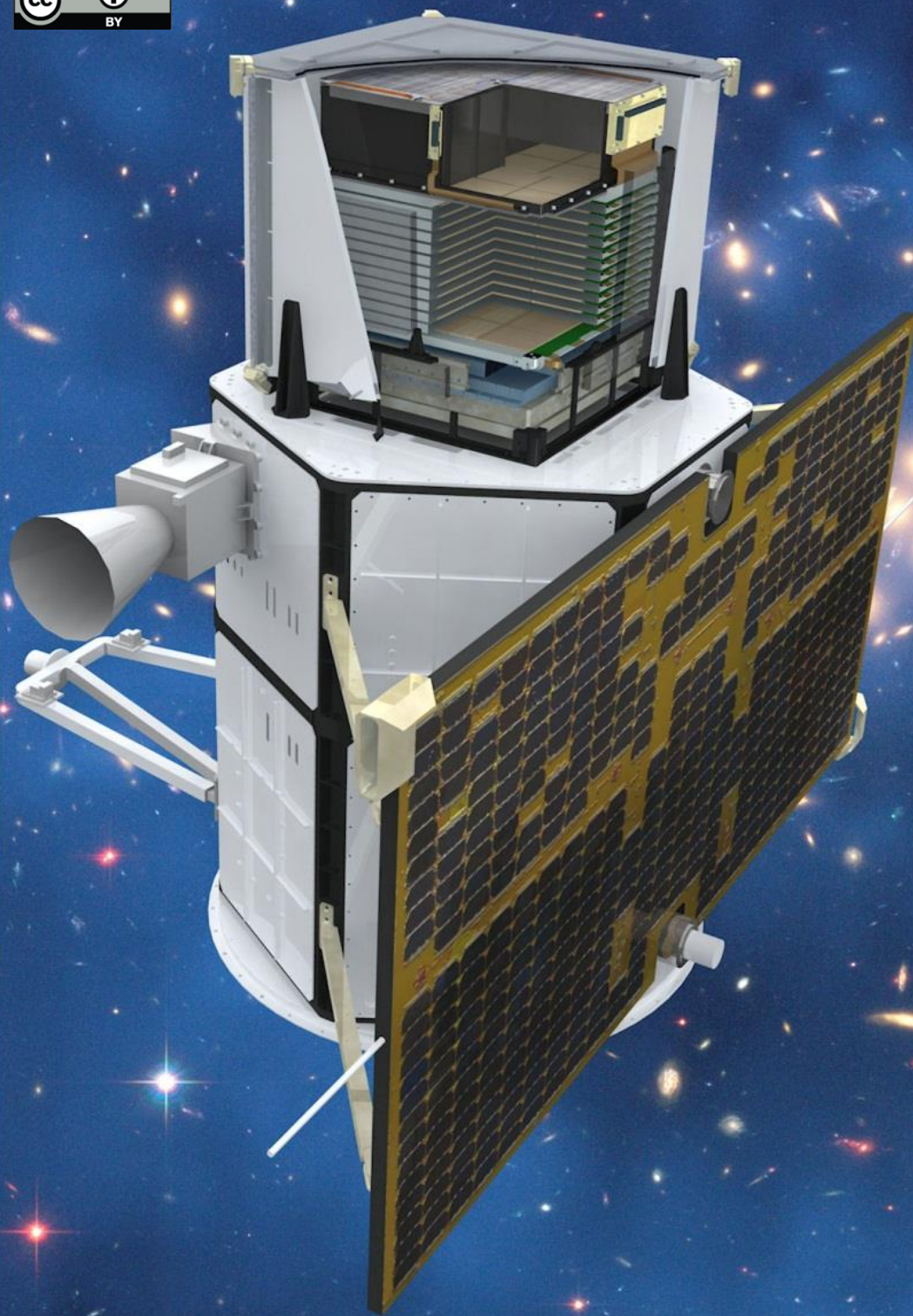
EGU General Assembly

Wien, April 9, 2013



**AGILE Satellite
(IABG, Munich
16 June, 2006)**

350 kg satellite



The AGILE Small Mission:

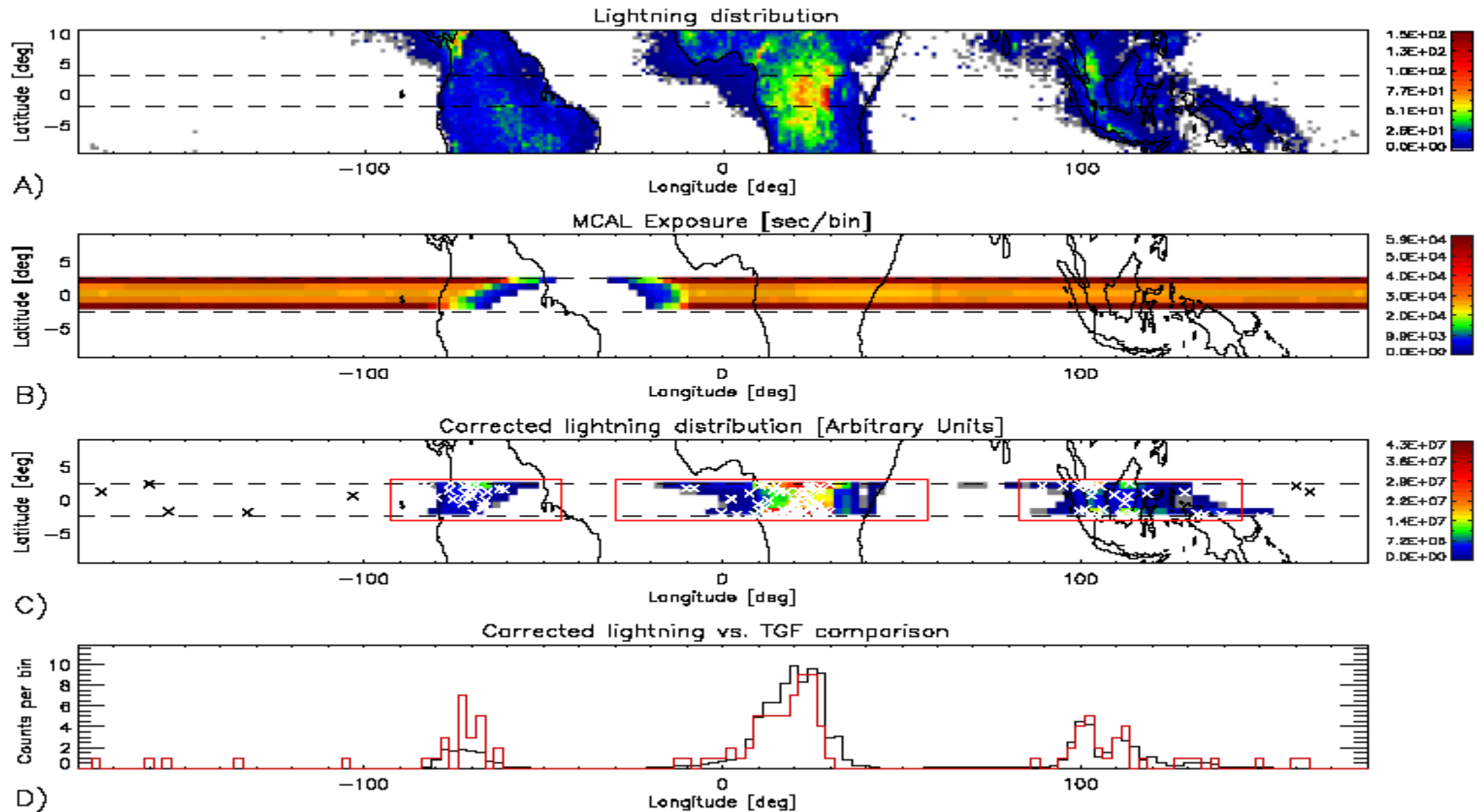
It combines for the first time a **gamma-ray imager** (50 MeV- 30 GeV) with a **hard X-ray imager** (18-60 keV) with large FOVs (1-2.5 sr) and optimal angular resolution

- AGILE special trigger capability
- MCAL burst search from sub-ms to seconds
 - TGFs detected by the trigger logic working in the timescale range $0.3 \text{ ms} < \tau < 16 \text{ ms}$

*** about 500 TGFs detected since 2009

*** about 300 are with good S/N ratio
energy range 0.4 – 100 MeV

TGF-lightning correlation

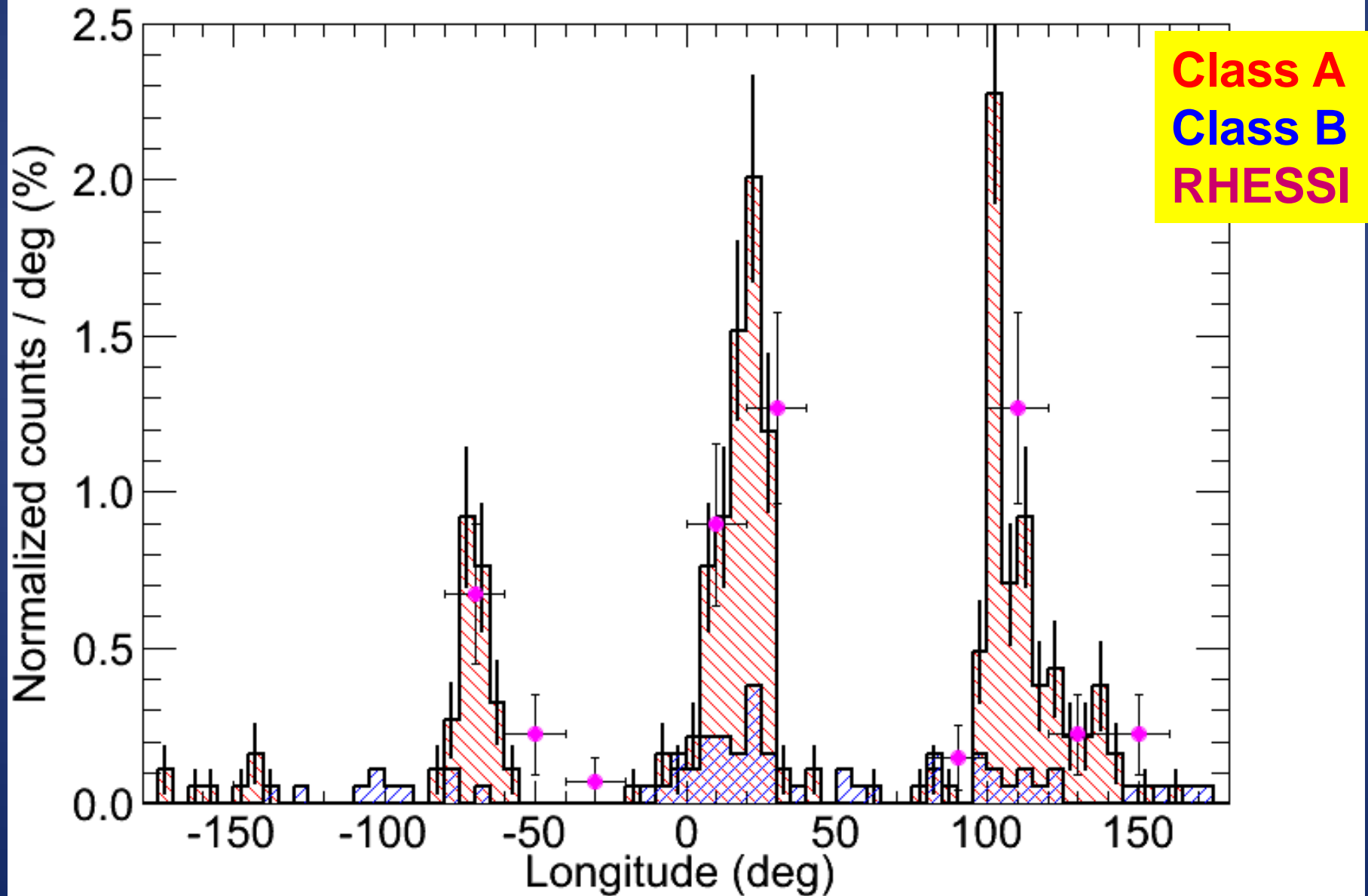


0.68 correlation coefficient for a global fit F. Fuschino et al. 2011

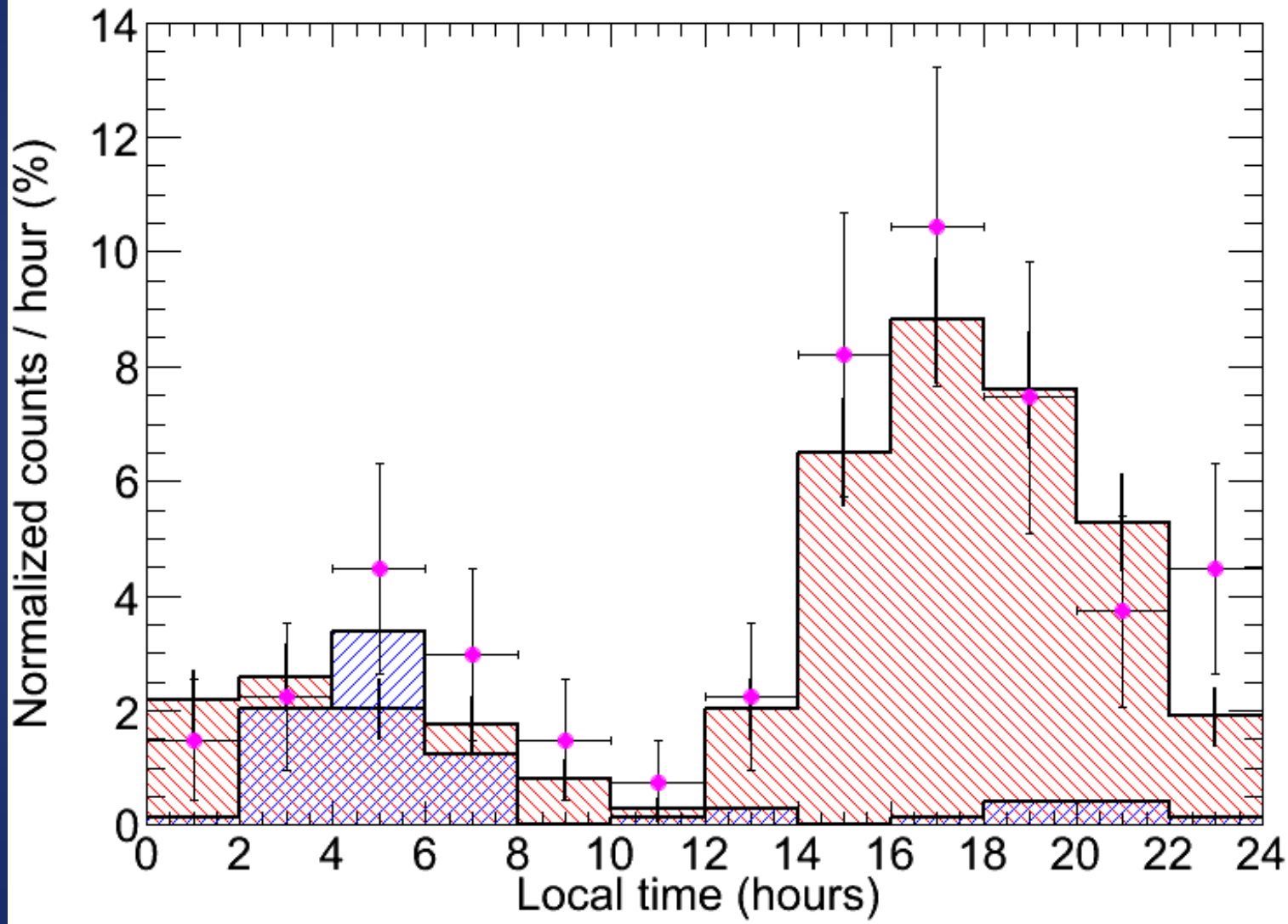
Continental region	TGF / flash ratio
America	$1.5 \cdot 10^{-4}$
Africa	$6.0 \cdot 10^{-5}$
South East Asia	$7.5 \cdot 10^{-5}$
All	$7.8 \cdot 10^{-5}$

Longitude distribution

$$E_{\text{MAX}} < 30 \text{ MeV}$$



Local time distribution



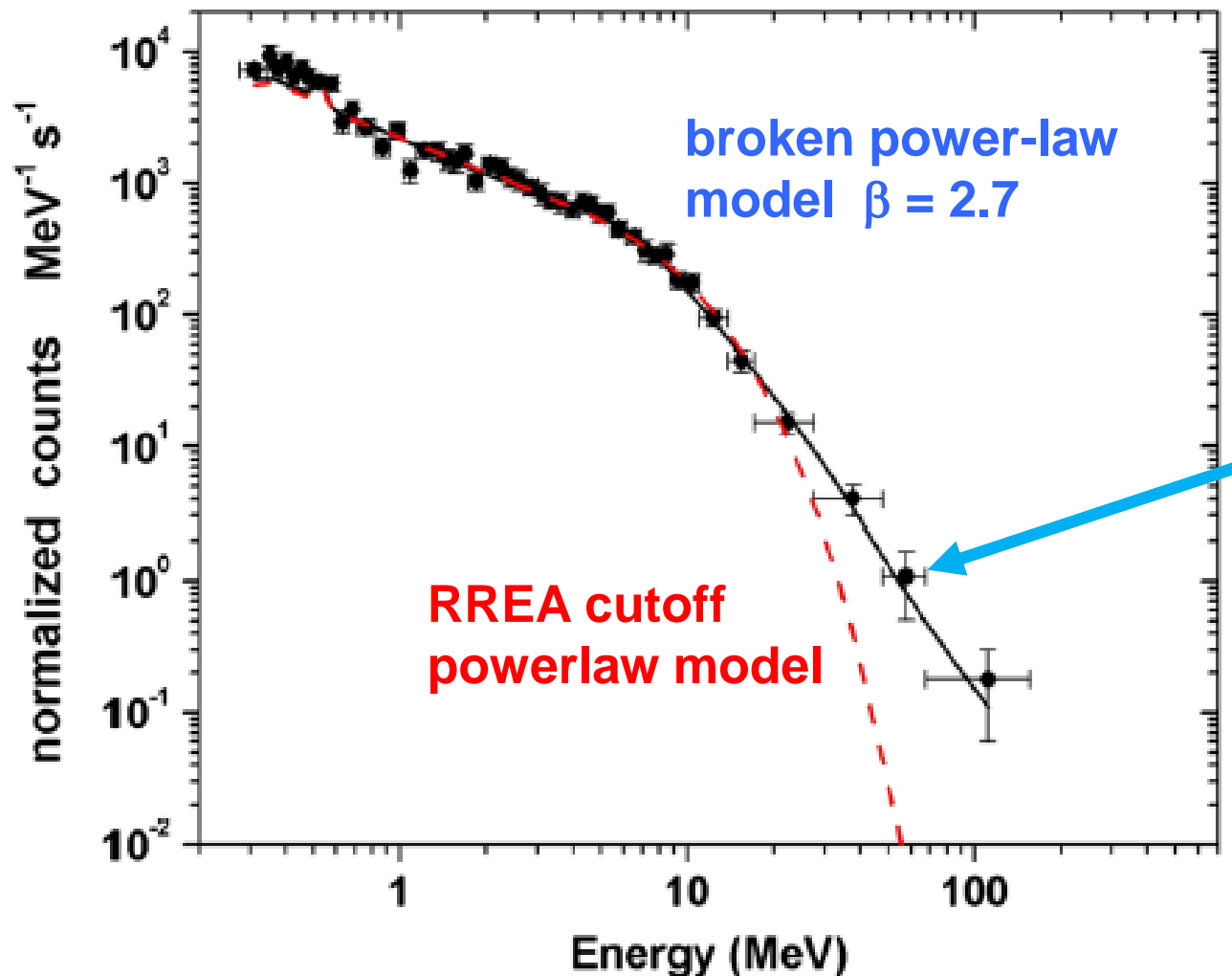
Class A
Class B
RHESSI

TFG cumulative spectrum

Tavani et al., Phys. Rev. Letters 106, 018501 (2011)

110 TGFs

26 events $E_{\text{max}} > 20$ MeV



significant detection of γ -rays with $E > 40$ MeV unexplained by standard RREA models: a challenge for emission models

Nat. Hazards Earth Syst. Sci., 13, 1–7, 2013
www.nat-hazards-earth-syst-sci.net/13/1/2013/
doi:10.5194/nhess-13-1-2013
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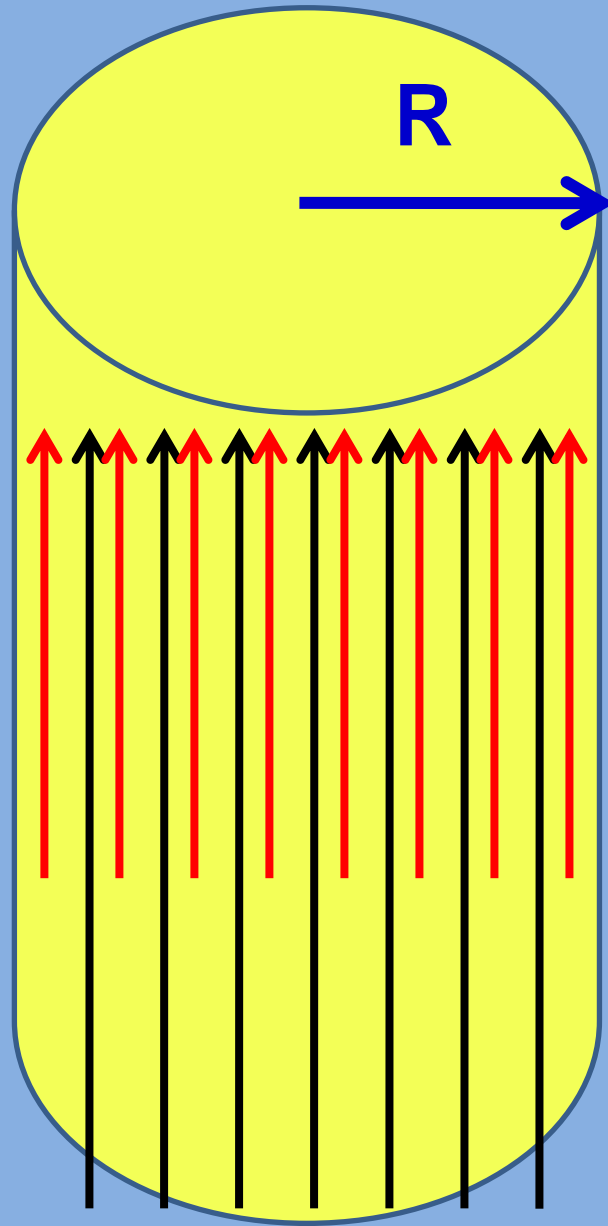


Natural Hazards
and Earth System
Sciences

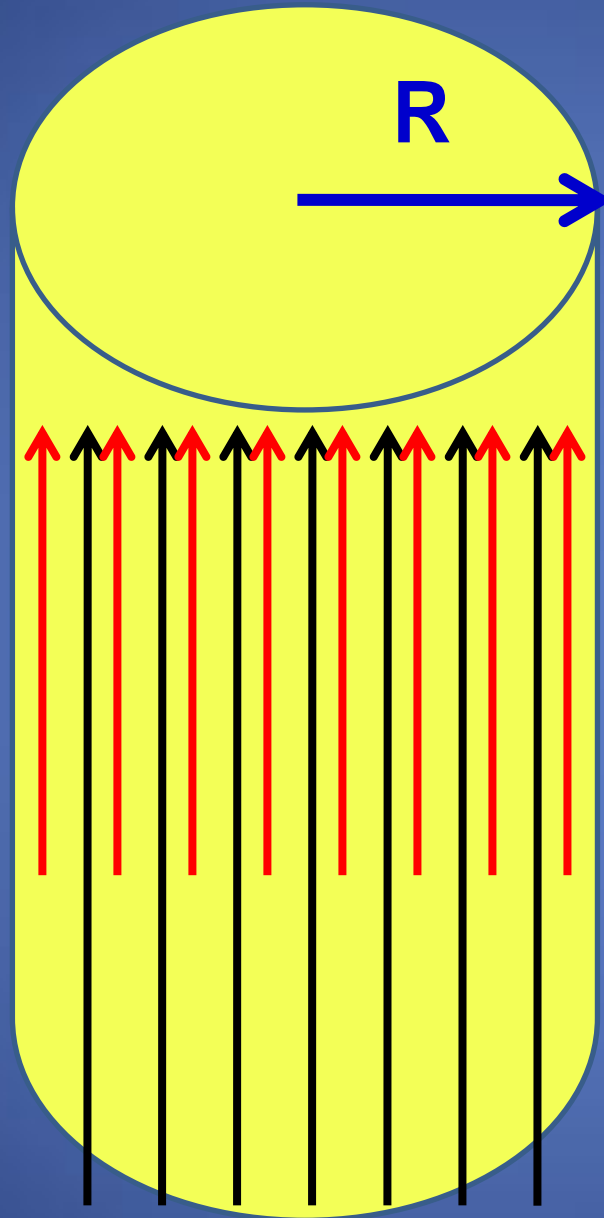


Possible effects on avionics induced by terrestrial gamma-ray flashes

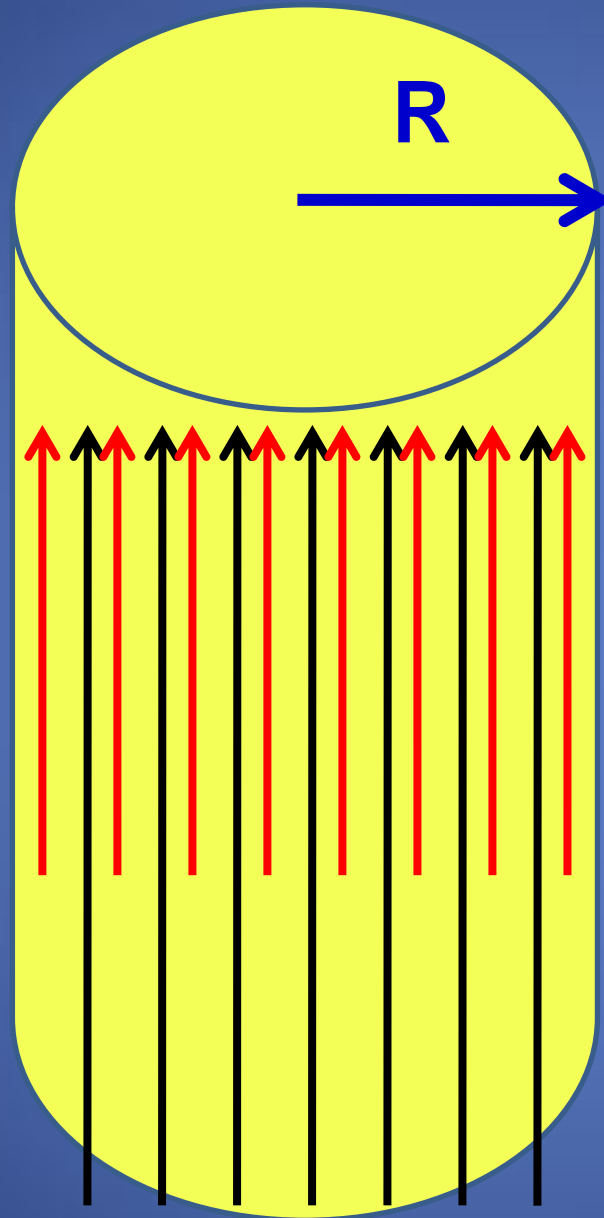
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TGF active channel



TGF active channel

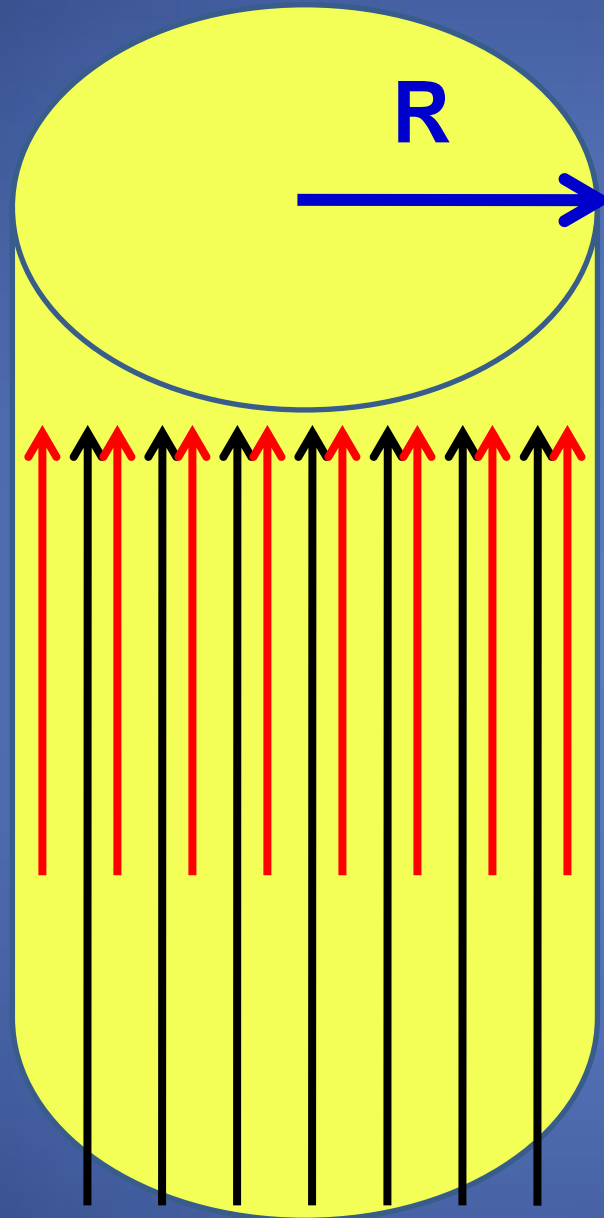


$$N = N_{17} 10^{17}$$

$$R = R_3 10^3 \text{ cm}$$

$$\tau = \tau_{-5} 10^{-5} \text{ sec}$$

TGF active channel



$$N = N_{17} 10^{17}$$

$$R = R_3 10^3 \text{ cm}$$

$$\tau = \tau_{-5} 10^{-5} \text{ sec}$$

define

$$X = N_{17} R_3^{-2}$$

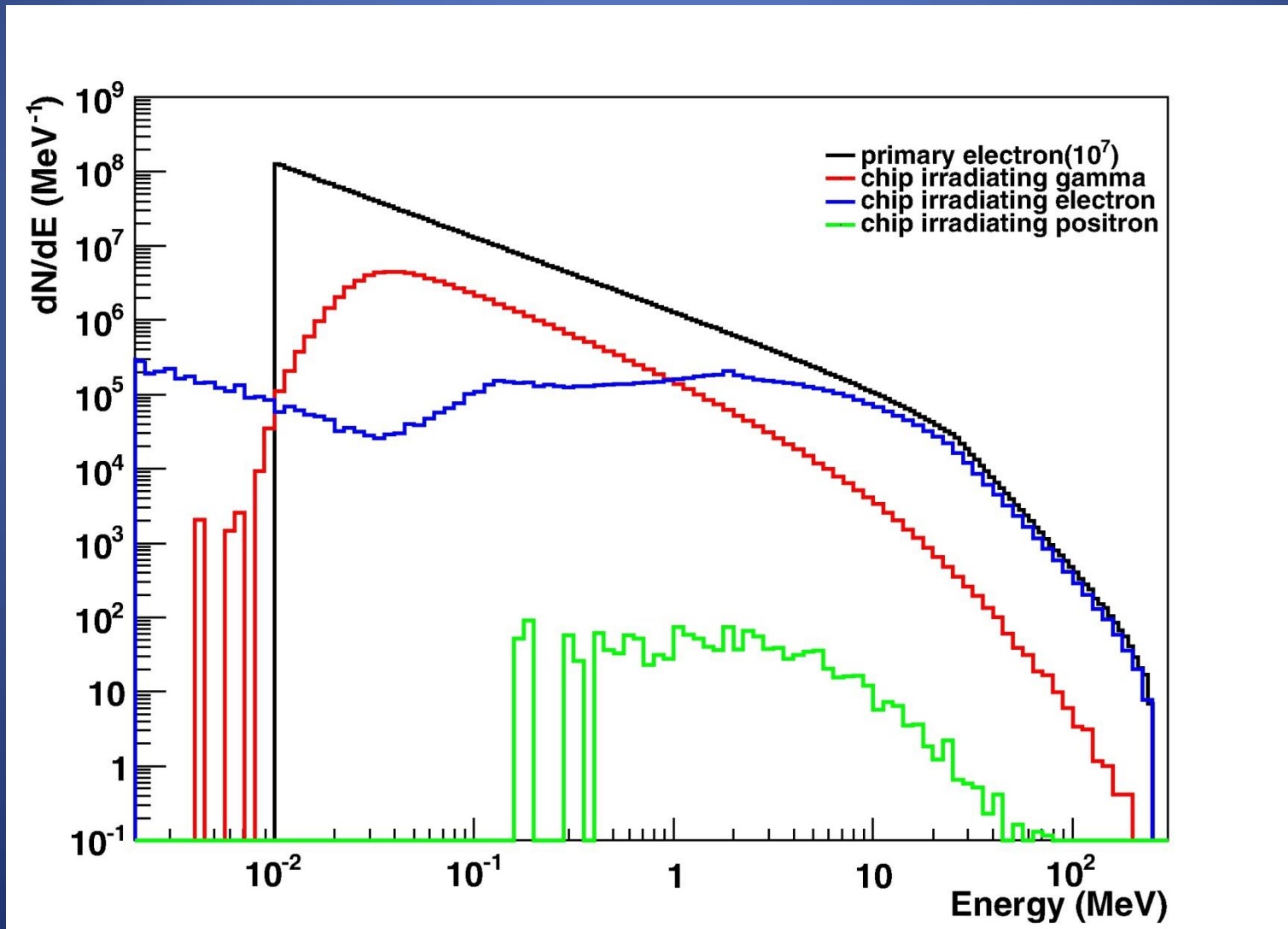
2 main components of radiation/particles within the aircraft

- electromagnetic component
 - electrons/positrons
 - gamma-rays
- neutron component

Possible effects on aircraft electronics

- **TID (total ionizing dose) effects**, cumulative effects causing charge trapping and interface state generation in dielectric layers.
- **DD (displacement damage) effects**, cumulative effect of ionizing and non-ionizing radiation displacing lattice atoms with parametric variations.
- **DR (dose rate) effects**, produced by intense bursts of ionizing radiation delivered within a few tens of microseconds causing upsets and latch-ups;
- **SEE (single event) effects**, caused by a single ionizing particle hitting a sensitive device.

Transport of primary electrons producing secondary electrons, positrons, gamma's [$L(\text{Al}) = 0.5 \text{ cm}$]



- For shielded electronic components the total e.m. dose is $D = (200 \text{ rad}) N_{17} R_3^{-2}$
- for unshielded components, D is ~30 % higher (see also Dwyer et al. 2011)

- this dose is accumulated within τ
- the dose rate is

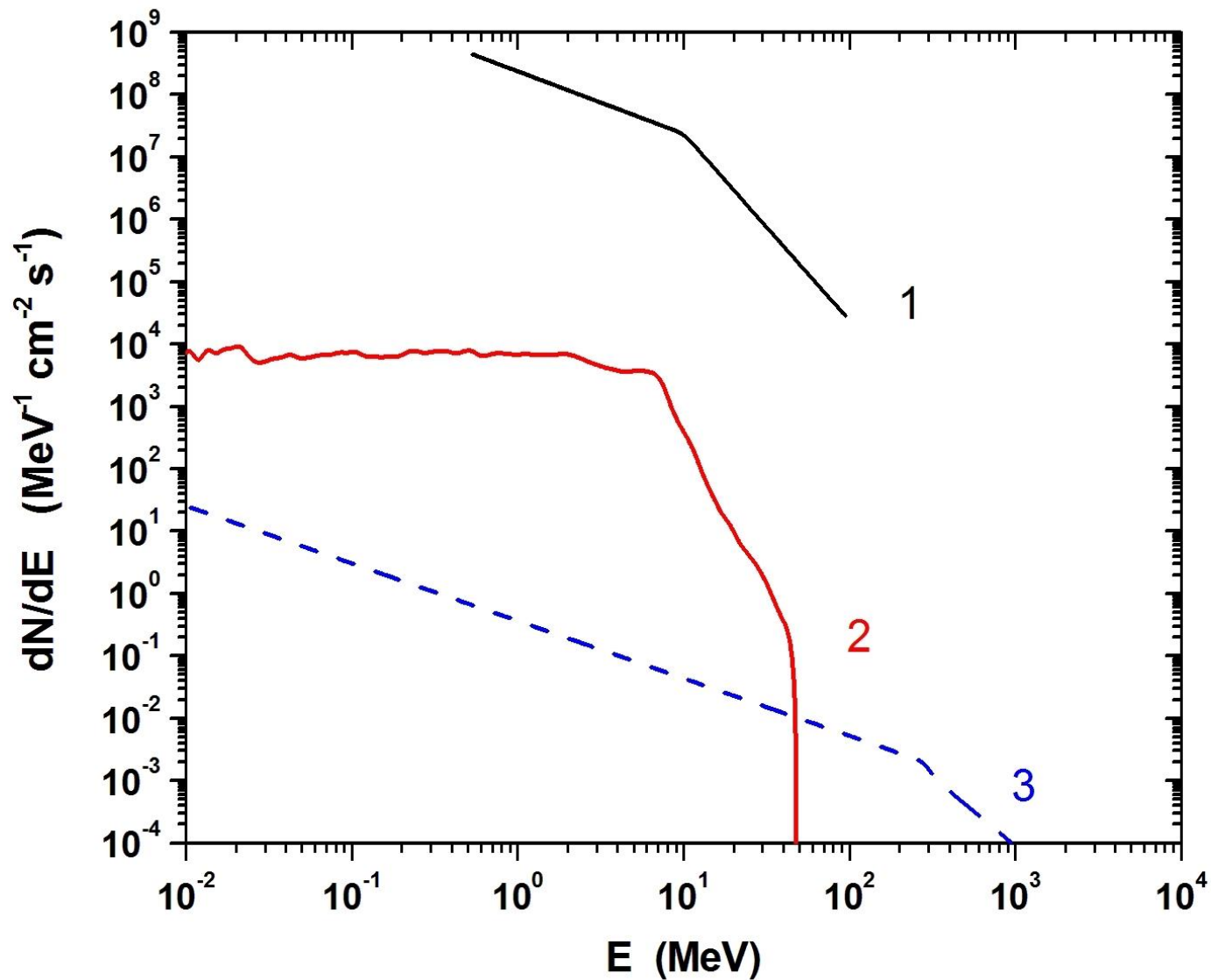
$$dD/dt = (2 \times 10^7 \text{ rad s}^{-1}) N_{17} R_3^{-2} \tau_{-5}$$

Neutrons

- neutrons induced in the atmosphere by lightning and TGFs were considered by, e.g. Babich et al (2008...) and Carlson et al. (2010).
- **we consider here neutron photo-production in an aircraft structure (of equivalent Al depth L): probability = $6 \times 10^{-4} (L/1\text{cm})$**
- **Prompt photo-produced neutron (PPN) spectrum and total flux**

$$F_n = (10^{10} \text{ cm}^{-2} \text{ s}^{-1}) N_{17} R_3^{-2} \tau_{-3}^{-1} (L/1 \text{ cm})$$

Neutron (PPN) flash (red, 2)



Possible effects

- DD and TID are usually not relevant for $X < 1$, they may become relevant for **$X > 25$** (in this case the dose can be very high also for humans, $D > 5 \times 10^3$ rad(Si), see Dwyer et al. 2010).
- **Dose rate (DR) and SEE effects** can be produced by very rapid and collective effects (circuit upsets, latchups and burnout if delivered within a timescale shorter than 1 ms).

Possible effects

- Assuming a critical level of malfunction ($D = 10^8 \text{ rad(Si) s}^{-1}$), we obtain a DR malfunction condition

$$X \tau_5^{-1} \sim 5$$

Possible effects

- **SEU (single event upset) effects** on aircraft electronics are mostly due to neutrons (Normand et al. 2006).
- For TGF irradiation, we consider PPN on benchmark electronics such as SRAMs., SEU cross-sections per bit for 4 Mbit SRAMs for neutron energies near 10 MeV

$$\sigma(\text{SEU cross-section/bit}) \simeq \alpha 3 \times 10^{-13} \text{ cm}^2 \quad (4)$$

$$\sigma(\text{SEU cross-section/device}) \simeq \alpha \times 10^{-6} \text{ cm}^2, \quad (5)$$

where α ($0 < \alpha < 1$) takes into account the measurement scatter for different SRAM manufacturers. From Eq. (5) and

Possible effects

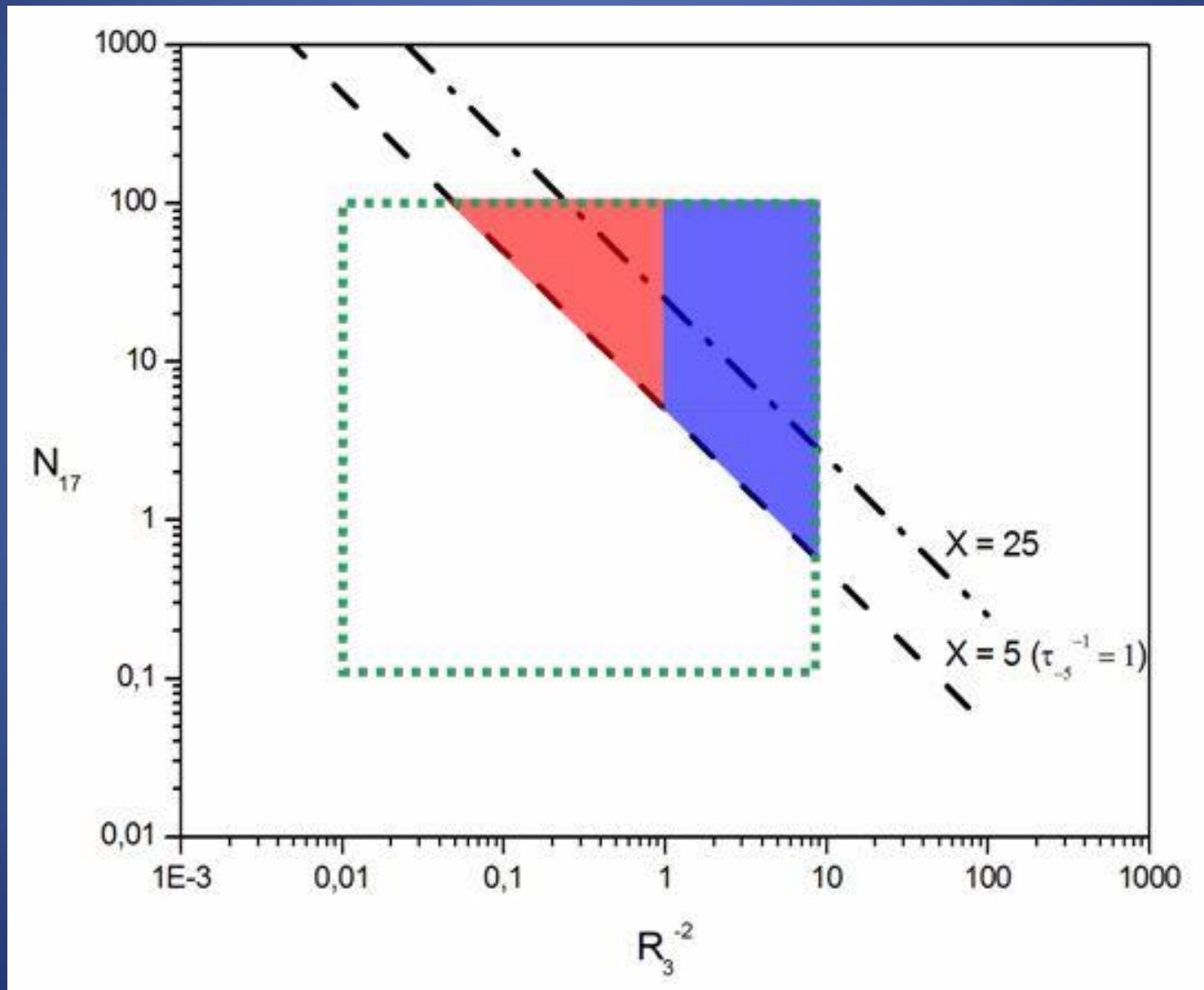
- The SEU probability per SRAM device induced by TGF PPN is

$$P \sim 10 \alpha X L$$

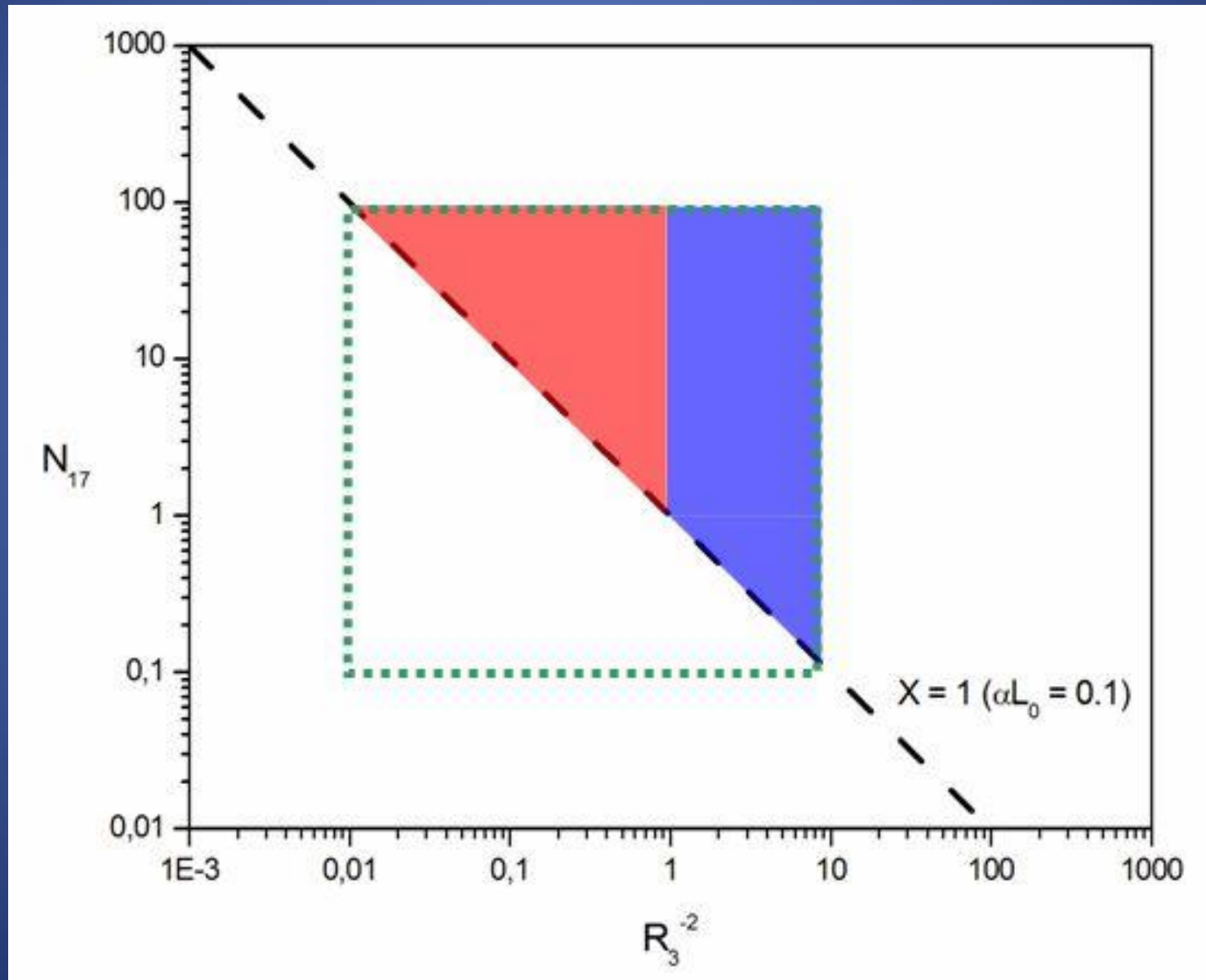
Table 1. Susceptibility to TGFs.

TGF strength	Radiation effects
$\alpha X L_o > 0.1$	significant neutron-induced SEEs
$X \geq 25$	total dose effects in sensitive components
$X \tau_{-5}^{-1} \sim 5$	dose rate effects

Possible critical parameter space (e.m. irradiation)



Possible critical parameter space (neutron irradiation)



Conclusions

- Depending on TGF strength and geometry of possible interaction with aircraft, critical susceptibility of simultaneously affected electronic equipment can be reached:
 - for PPN neutrons for $\alpha X L \sim 0.1$;
 - for the e.m. component for $X > 25$ or $X \tau_5^{-1} \sim 5$.
- Depending on internal redundancy and protection, the overall aircraft electronic system may recover or possibly be affected.
- Definitely, additional work is needed:
 - improved measurements (ground, aircraft, satellite);
 - susceptibility studies for highly variable regimes;
 - realistic simulations.